

Description

The AP220N08TLG1 uses advanced **APM-SGT I** technology to provide excellent $R_{DS(ON)}$, low gate charge and operation with gate voltages as low as 10V.

This device is suitable for use as a Battery protection or in other Switching application.

General Features

$V_{DS} = 80V$ $I_D = 220A$

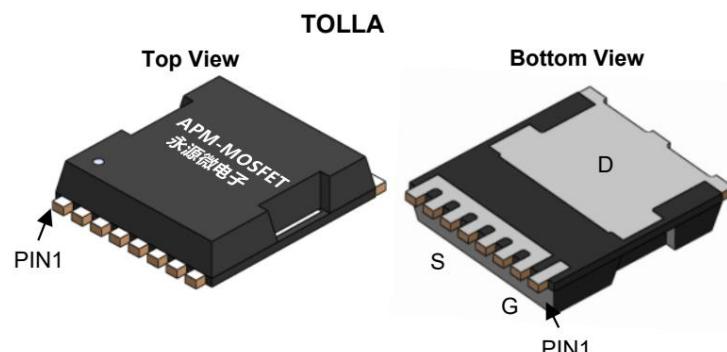
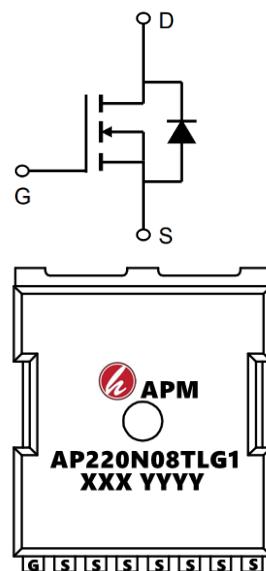
$R_{DS(ON)} < 3.2m\Omega$ $V_{GS}=10V$ (**Type: 2.4m Ω**)

Application

Battery protection

Load switch

Uninterruptible power supply



Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
AP220N08TLG1	TOLLA-8L	AP220N08TLG1 XXX YYYY	2000

Absolute Maximum Ratings ($T_c=25^\circ C$ unless otherwise noted)

Symbol	Parameter	Rating	Units
V_{DS}	Drain-Source Voltage	80	V
V_{GS}	Gate-Source Voltage	± 20	V
$I_D @ T_c=25^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$	220	A
$I_D @ T_c=100^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$	110	A
I_{DM}	Pulsed Drain Current	480	A
E_{AS}	Single Pulse Avalanche Energy	858	mJ
$P_D @ T_c=25^\circ C$	Total Power Dissipation ⁴	284	W
T_{STG}	Storage Temperature Range	-55 to 150	°C
T_J	Operating Junction Temperature Range	-55 to 150	°C
$R_{\theta JA}$	Thermal Resistance Junction-Ambient	0.53	°C/W
$R_{\theta JC}$	Thermal Resistance Junction-Case	62.5	°C/W

Electrical Characteristics ($T_j=25^\circ\text{C}$, unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
V(BR)DSS	Drain-source breakdown voltage	$V_{GS}=0\text{V}, I_D=250\mu\text{A}$	80	92		V
VGS(th)	Gate threshold voltage	$V_{DS}=V_{GS}, I_D=250\mu\text{A} T_j=25^\circ\text{C}$	2.0	3.0	4.0	V
IDSS	Zero gate voltage drain current	$V_{DS}=80\text{V}, V_{GS}=0\text{V} T_j=25^\circ\text{C}$	-		1	μA
IDSS	Zero gate voltage drain current	$V_{DS}=80\text{V}, V_{GS}=0\text{V} T_j=125^\circ\text{C}$		- 5		μA
IGSS	Gate-source leakage current	$V_{GS}=20\text{V}, V_{DS}=0\text{V}$	-	-	100	nA
RDS(on)	Drain-source on-state resistance	$V_{GS}=10\text{V}, I_D=50\text{A}, T_j=25^\circ\text{C}$	-	2.4	3.2	$\text{m}\Omega$
gfs	Transconductance	$V_{DS}=5\text{V}, I_D=40\text{A}$	-	106	-	S
Ciss	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=40\text{V}, f=1\text{MHz}$	-	6813	-	pF
Coss	Output Capacitance		-	808	-	pF
Crss	Reverse Transfer Capacitance		-	48	-	pF
QG	Gate Total Charge	$V_{GS}=10\text{V}, V_{DS}=40\text{V}, I_D=25\text{A}$	-	91	-	nC
Qgs	Gate-Source charge		-	37	-	nC
Qgd	Gate-Drain charge		-	25	-	nC
td(on)	Turn-on delay time	$T_j=25^\circ\text{C}, V_{GS}=10\text{V}, V_{DS}=40\text{V}, R_L=3\Omega$	-	38	-	ns
t _r	Rise time		-	58	-	ns
td(off)	Turn-off delay time		-	63	-	ns
t _f	Fall time		-	32	-	ns
R _G	Gate resistance	$V_{GS}=0\text{V}, V_{DS}=0\text{V}, f=1\text{MHz}$	-	2	-	Ω
VSD	Body Diode Forward Voltage	$V_{GS}=0\text{V}, I_{SD}=50\text{A}$	-	0.85	1.2	V
trr	Body Diode Reverse Recovery Time	$I_F=20\text{A}, dI/dt=500\text{A}/\mu\text{s}$	-	85	-	ns
Qrr	Body Diode Reverse Recovery Charge		-	313	-	nC

Note :

- 1、The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper.
- 2、The data tested by pulsed , pulse width .The EAS data shows Max. rating .
- 3、The test cond \equiv 300us duty cycle \leq 2%, duty cycle ition is $V_{DD}=64\text{V}$, $V_{GS}=10\text{V}$, $L=0.1\text{mH}$, $I_{AS}=53.8\text{A}$
- 4、The power dissipation is limited by 175°C junction temperature
- 5、The data is theoretically the same as ID and IDM , in real applications , should be limited by total power dissipation.



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AP220N08TLG1

80V N-Channel Enhancement Mode MOSFET

Typical Characteristics

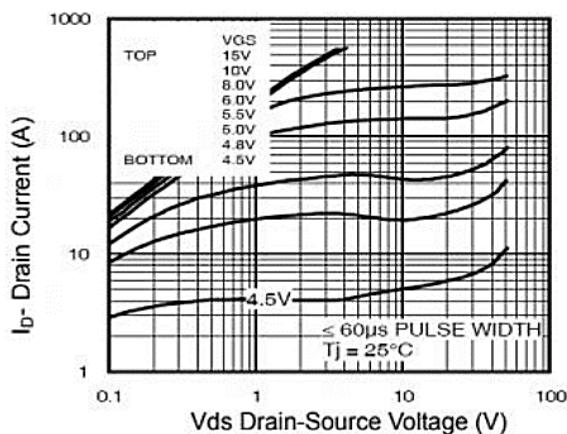


Figure 1 Output Characteristics

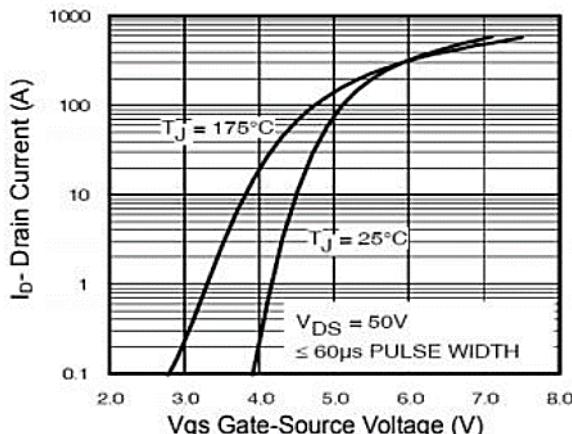


Figure 2 Transfer Characteristics

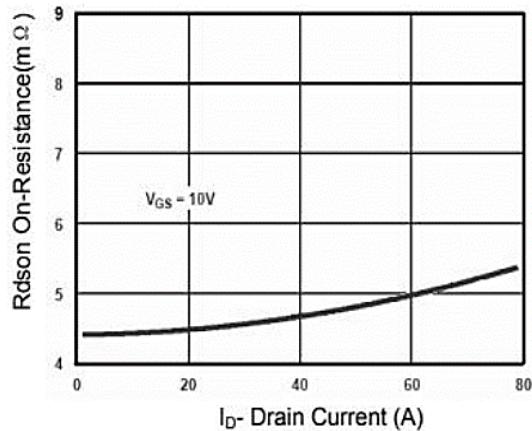


Figure 3 Rdson- Drain Current

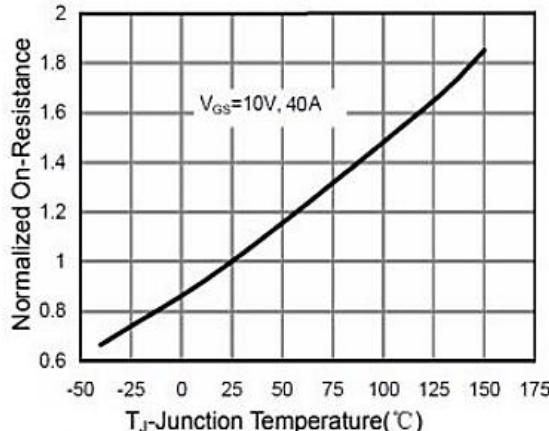


Figure 4 Rdson-JunctionTemperature

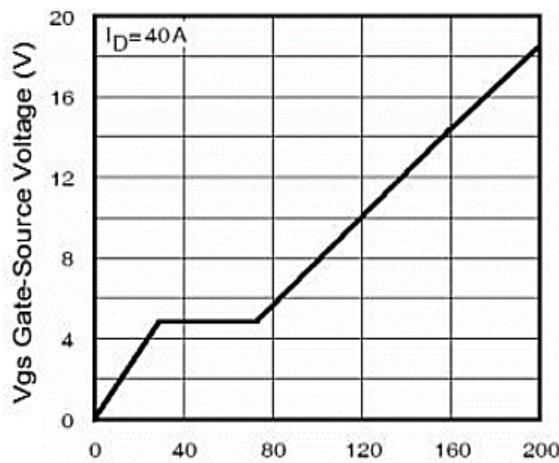


Figure 5 Gate Charge

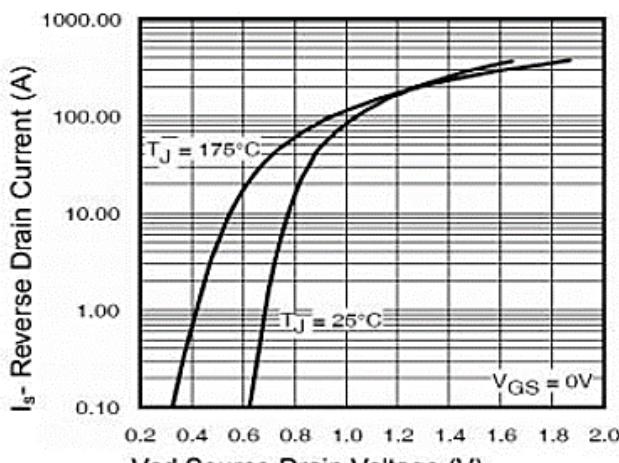


Figure 6 Source- Drain Diode Forward





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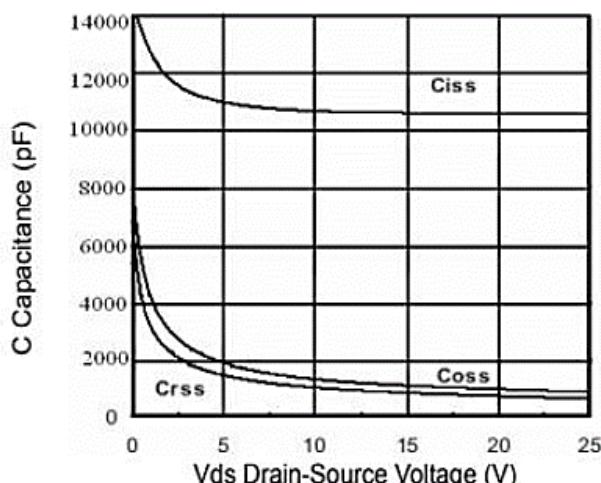


Figure 7 Capacitance vs Vds

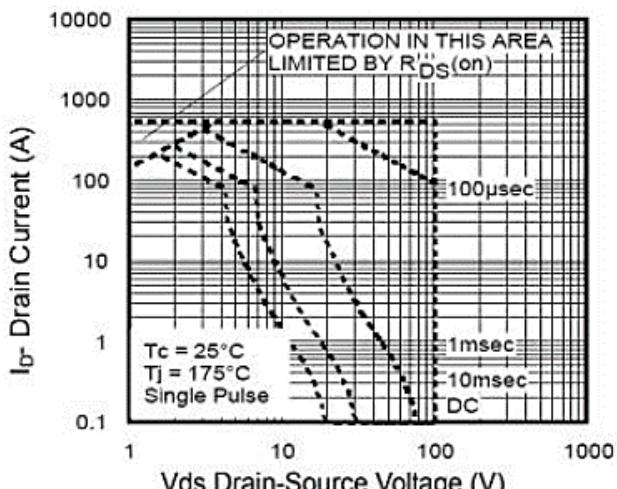


Figure 8 Safe Operation Area

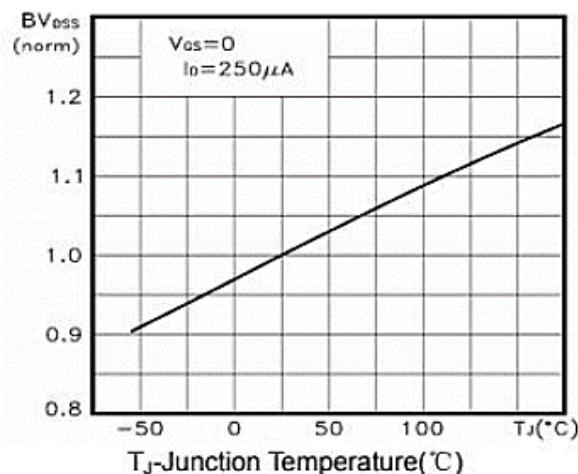
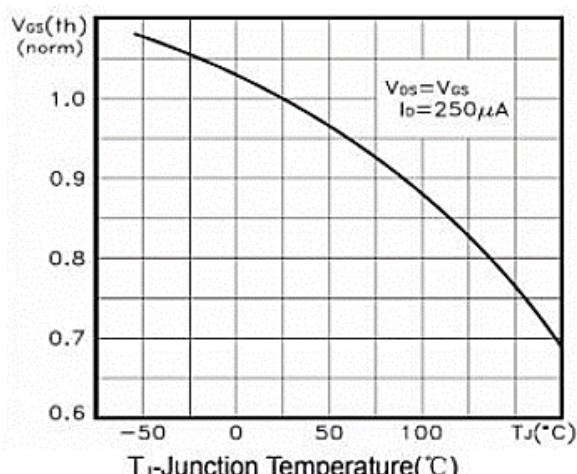
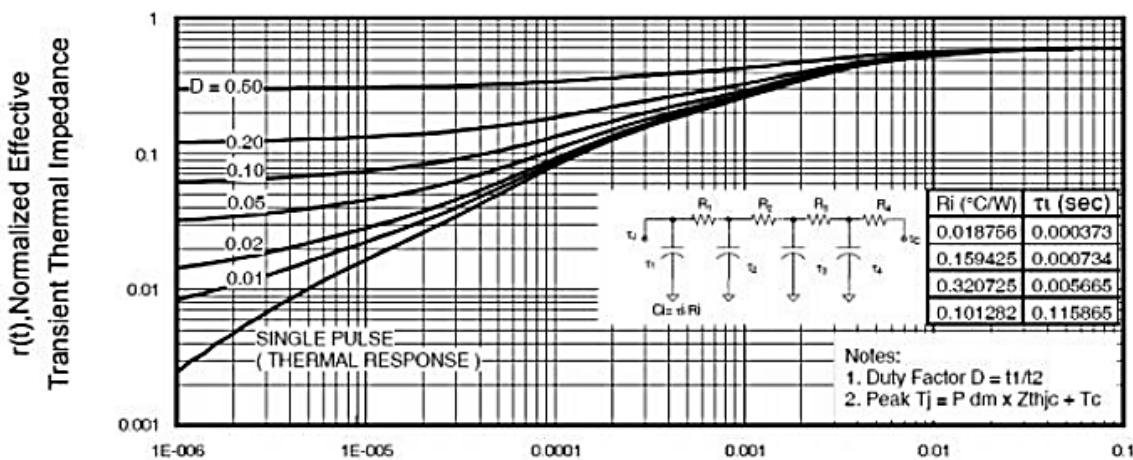
Figure 9 BV_{DSS} vs Junction TemperatureFigure 10 V_{GS(th)} vs Junction Temperature

Figure 11 Normalized Maximum Transient Thermal Impedance

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Edition	Date	Change
Rve1.0	2020/10/31	Initial release

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